Efficient Testing Solutions



Non-Contact Sheet Resistance **Tester**



DATA SHEET - EddyCus® TF lab 2020

HIGHLIGHTS

- Contact-free & real-time
- Accurate single-point measurement of sheet resistance for conductive thin films (Ohm/sq)
- Layer thickness measurement of metal films (nm)
- Wall thickness monitoring of low and high conductive substrates (µm)
- Characterization of multilayer systems
- Manual mapping of sheet resistance guided by an easy-to-handle software

APPLICATIONS

- > Architectural glass (LowE)
- > Touch screens & flat monitors
- > OLED & LED applications
- > Smart-glass applications
- > Transparent antistatic foils
- > Photovoltaics
- > Semiconductors
- > De-icing & heating applications
- > Batteries & fuel cells
- > Packaging materials





















DATA SHEET

EddyCus® TF lab 2020 - Sheet Resistance Tester



Substrate area Max. sample thickness/sensor gap (defines distances) Sheet resistance range

Thickness measurement of thin films (e.g. copper)

Device dimension (w/h/d)

Weight

8 inch / 204 x 204 mm² (open to three sides)

1/2/5/10/25 mm (defined by the thickest sample / application)

0.001 - 10 Ohm/sq < 2 % accuracy 10 - 300 Ohm/sq < 3 % accuracy 300 - 1,000 Ohm/sq < 5 % accuracy higher range on request

1 nm - 500 µm (in accordance with sheet resistance)

290 x 445 x 140 mm³

10 kg

SOFTWARE & HANDLING - EddyCus® TF lab Control

